

# **FSD 01 Measurements**

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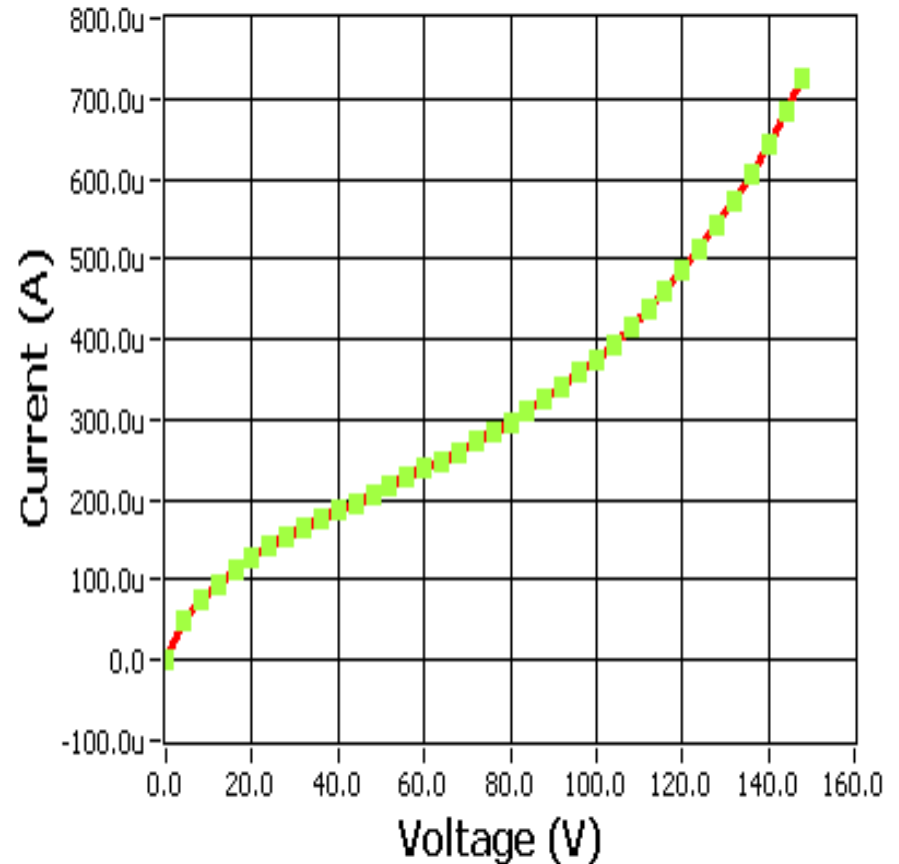
# Outline

- ❖ **Measurements of FSD 01 Detectors**
- ❖ **Overview of the Good Detectors**

# FSD 01 Wafer-01

( $\phi=3e13$  n/cm<sup>2</sup>)

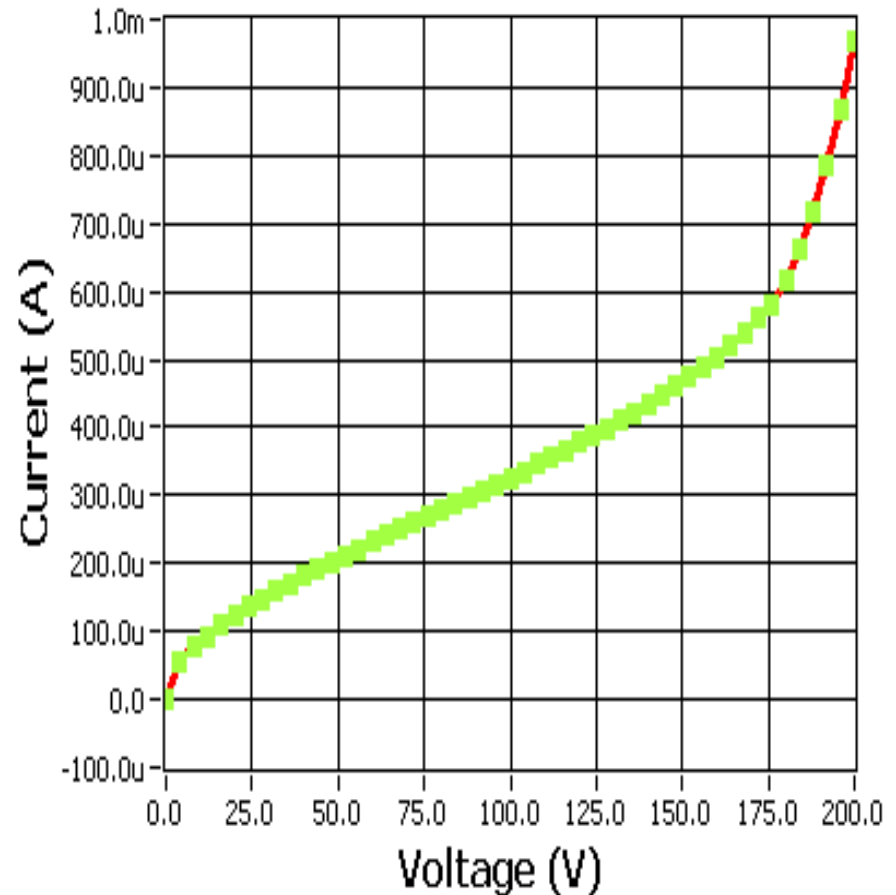
- Pinholes testing:  
No Pinholes
- $V_{fd}$  = not Observed till  
150V biasing
- Breakdown V= Not  
observed till 150V
- Room Tempt Annealing:  
7hrs.



# FSD 01 Wafer-22

( $\phi=1e14$  n/cm<sup>2</sup>)

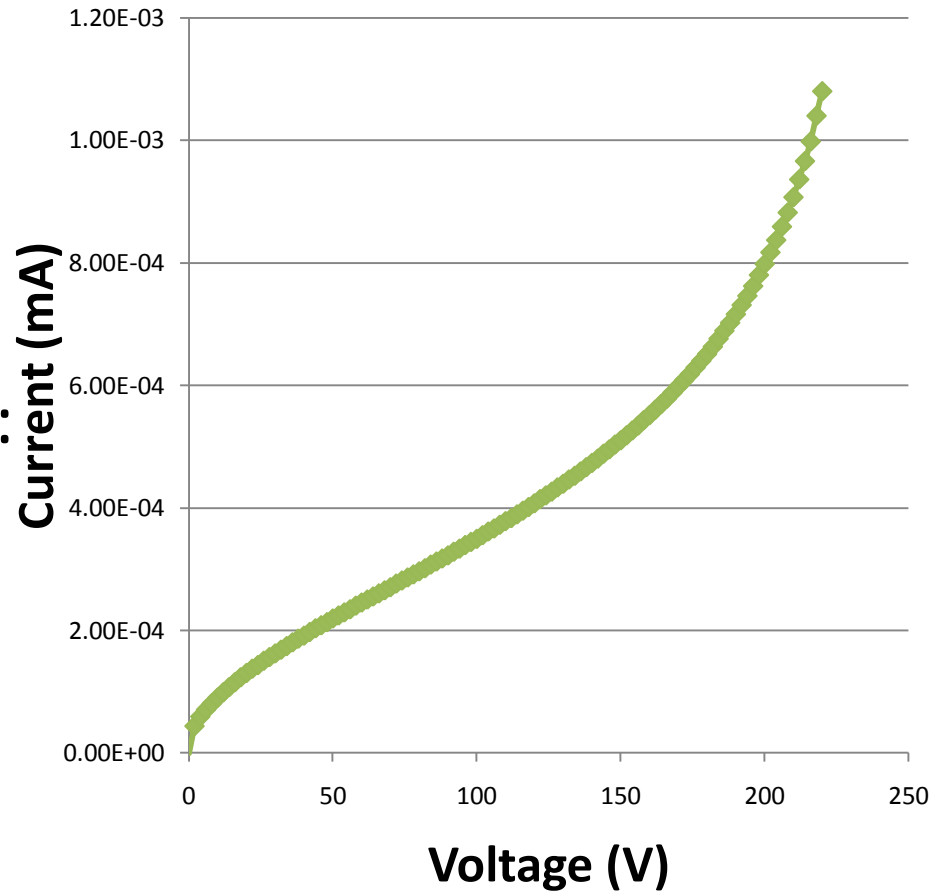
- Pinholes testing:
  - No Pinholes on p-side
  - #186 shorted on n-side
- $V_{fd}$  = not Observed till 200V biasing
- Breakdown V= observed at 176V
- Room Tempt Annealing: 18hrs 40mins



# FSD 01 Wafer-08

( $\phi=1e14$  n/cm<sup>2</sup>)

- $V_{fd}$  = not Observed till 220V biasing
- Breakdown V= Not observed till 220V
- Room Tempt Annealing: 6hrs 30mins



# Overview of Good Detectors

Detectors	Wafer-24 (1e12 n/cm <sup>2</sup> )	Wafer-03 (1e13 n/cm <sup>2</sup> )	Wafer-01 (3e13 n/cm <sup>2</sup> )	Wafer-22 (1e14 n/cm <sup>2</sup> )	Wafer-08 (1e13 n/cm <sup>2</sup> )
Pin hole test	No Pinholes	No Pinholes	No Pinholes	#186 on n side	--
Full Depletion Voltage	30V	15V	Not Observed	Not Observed	Not Observed
Breakdown Voltage	Not Observed	Not Observed	Not Observed	176V	Not Observed
Annealing at Room Temperature	7hrs 36mins	122hrs	7hrs	18hrs 40mins	6hrs 30mins
Remarks	Tested Last Week	Tested Last Week	Tested this Week	Tested this Week	Tested this Week